

Search Notes



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Examiner

José V. Chen

Applicant(s)/Patent under Reexamination

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Art Unit

3637

SEARCHED

Class	Subclass	Date	Examiner
108	180	6/7/05	JLC
	105		
	186		
	187		
	190		
	143		
	153e1		
	155		
	157.18		
	158.12		
312	257e1		
	265.1		
	265.2		
	195		
240	180		
	188e1		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Front & Front & back. Citations for PCT Art	6/7/05	JLC